

FORM PTO 1449 (modified)

ATTY DOCKET NO.
684.2925APPLICATION NO.
09/428,490U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEAPPLICANT
HIDEKI INA, ET AL.LIST OF REFERENCES CITED BY APPLICANT(S)
(Use several sheets if necessary)FILING DATE
October 28, 1999GROUP
2873Submitted to the PTO: **August 16, 2000**

U.S. PATENT DOCUMENTS

*EXAMINER	DOCUMENT					FILING DATE

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)

<i>for</i>		Hiroshi Kubota, "Wave Optics", Iwanami Shoten Co., pp. 414-415.
<i>↓</i>		"Needs and Seeds of Optical Measurement", edited by Shadan-Hojin Keiryo Kanri Kyokai and Hikari Oyous Keisoku Gijutsu Chosa Kenkyu linkai, Corona Co., pp. 228-229.
<i>↓</i>		"New Optical Microscopes", Vol. 1, "Theory and Practice of Laser Microscopes", supervised by Tetsuya Fujita, edited by Minoru Kawada, Gakusai-Kikaku Co., pp. 82-83.

EXAMINER

DATE CONSIDERED

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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Sheet 1 of 1



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U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		APPLICANT Hideki INA et al.			
LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)		FILING DATE October 28, 1999		GROUP 2873	
April 10, 2002					
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*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS SUBCLASS FILING DATE IF APPROPRIATE
<i>JCM</i>		4,869,593	09/26/1989	Biegen	356 351
		5,783,342	07/21/1998	Yamashita et al.	430 30
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OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)					
EXAMINER		DATE CONSIDERED			
<i>PLN</i>		7/10/2			

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